

**General Description**

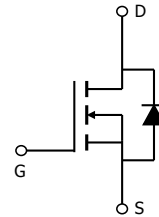
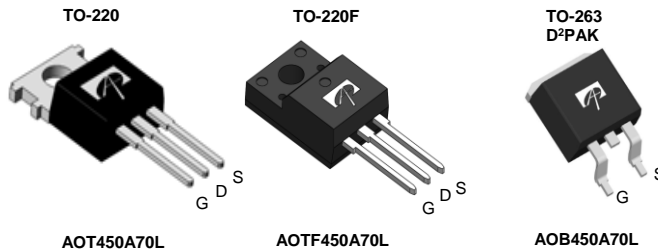
- Proprietary  $\alpha$ MOS5™ technology
- Low  $R_{DS(ON)}$
- Optimized switching parameters for better EMI performance
- Enhanced body diode for robustness and fast reverse recovery

**Applications**

- PFC and PWM stages (Flyback, LLC) of Adapter, PC Silverbox, Server, Gaming Power Supply, Industrial, TV, Lighting

**Product Summary**

$V_{DS} @ T_{j,max}$	800V
$I_{DM}$	44A
$R_{DS(ON),max}$	< 0.45 $\Omega$
$Q_{g,typ}$	20nC
$E_{oss} @ 400V$	2.5 $\mu$ J

 100% UIS Tested  
 100%  $R_g$  Tested


Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOT450A70L	TO-220	Tube	1000
AOTF450A70L	TO-220F	Tube	1000
AOB450A70L	TO263	Tape and reel	800

**Absolute Maximum Ratings  $T_A=25^\circ\text{C}$  unless otherwise noted**

Parameter	Symbol	AOT(B)450A70L	AOTF450A70L	Units
Drain-Source Voltage	$V_{DS}$	700		V
Gate-Source Voltage	$V_{GS}$	$\pm 20$		V
Gate-Source Voltage (dynamic) AC (f > 1Hz)	$V_{GS}$	$\pm 30$		V
Continuous Drain Current	$T_C=25^\circ\text{C}$	11	11*	A
	$T_C=100^\circ\text{C}$	7.1	7.1*	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	44		
Avalanche Current <sup>C</sup>	$I_{AR}$	2.5		A
Repetitive avalanche energy <sup>C</sup>	$E_{AR}$	3.1		mJ
Single pulsed avalanche energy <sup>G</sup>	$E_{AS}$	30		mJ
MOSFET dv/dt ruggedness	dv/dt	100		V/ns
Peak diode recovery dv/dt		20		
Power Dissipation <sup>B</sup>	$T_C=25^\circ\text{C}$	138	27	W
	Derate above 25°C	1.1	0.2	W/°C
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150		°C
Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	$T_L$	300		°C

**Thermal Characteristics**

Parameter	Symbol	AOT(B)450A70L	AOTF450A70L	Units
Maximum Junction-to-Ambient <sup>A,D</sup>	$R_{\theta JA}$	65	65	°C/W
Maximum Case-to-sink <sup>A</sup>	$R_{\theta CS}$	0.5	--	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	0.90	4.5	°C/W

\* Drain current limited by maximum junction temperature.

**Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units	
<b>STATIC PARAMETERS</b>							
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	700			V	
		I <sub>D</sub> =250μA, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C		800			
BV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V		0.6		V/°C	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V			1	μA	
		V <sub>DS</sub> =560V, T <sub>J</sub> =125°C			10		
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V			±100	nA	
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =5V, I <sub>D</sub> =250μA	2.4	3	3.6	V	
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =2.3A		0.405	0.45	Ω	
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> =2.3A		5		S	
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =2.3A, V <sub>GS</sub> =0V		0.8	1.2	V	
I <sub>S</sub>	Maximum Body-Diode Continuous Current				11	A	
I <sub>SM</sub>	Maximum Body-Diode Pulsed Current <sup>C</sup>				44	A	
<b>DYNAMIC PARAMETERS</b>							
C <sub>iSS</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =100V, f=1MHz		1115		pF	
C <sub>oSS</sub>	Output Capacitance				30		pF
C <sub>o(er)</sub>	Effective output capacitance, energy related <sup>H</sup>	V <sub>GS</sub> =0V, V <sub>DS</sub> =0 to 480V, f=1MHz		28		pF	
C <sub>o(tr)</sub>	Effective output capacitance, time related <sup>I</sup>				122		pF
C <sub>rSS</sub>	Reverse Transfer Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =100V, f=1MHz		2		pF	
R <sub>g</sub>	Gate resistance	f=1MHz		6.7		Ω	
<b>SWITCHING PARAMETERS</b>							
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =480V, I <sub>D</sub> =5.5A		20		nC	
Q <sub>gs</sub>	Gate Source Charge				6.8		nC
Q <sub>gd</sub>	Gate Drain Charge				5.2		nC
t <sub>D(on)</sub>	Turn-On DelayTime	V <sub>GS</sub> =10V, V <sub>DS</sub> =400V, I <sub>D</sub> =5.5A, R <sub>G</sub> =5Ω		25		ns	
t <sub>r</sub>	Turn-On Rise Time				15		ns
t <sub>D(off)</sub>	Turn-Off DelayTime				45		ns
t <sub>f</sub>	Turn-Off Fall Time				20		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time				275		ns
I <sub>rm</sub>	Peak Reverse Recovery Current	I <sub>F</sub> =5.5A, di/dt=100A/μs, V <sub>DS</sub> =400V		21		A	
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge			3.5		μC	

A. The value of R<sub>θJA</sub> is measured with the device in a still air environment with T<sub>A</sub>=25° C.

B. The power dissipation P<sub>D</sub> is based on T<sub>J(MAX)</sub>=150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature T<sub>J(MAX)</sub>=150° C. Ratings are based on low frequency and duty cycles to keep initial T<sub>J</sub>=25° C.

D. The R<sub>θJA</sub> is the sum of the thermal impedance from junction to case R<sub>θJC</sub> and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T<sub>J(MAX)</sub>=150° C. The SOA curve provides a single pulse rating.

G. This is the absolute maximum rating. Parts are 100% tested at T<sub>J</sub>=25° C, L=60mH, I<sub>AS</sub>=1A, V<sub>DD</sub>=150V, R<sub>G</sub>=25Ω.

H. C<sub>o(er)</sub> is a fixed capacitance that gives the same stored energy as C<sub>oSS</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>(BR)DSS</sub>.

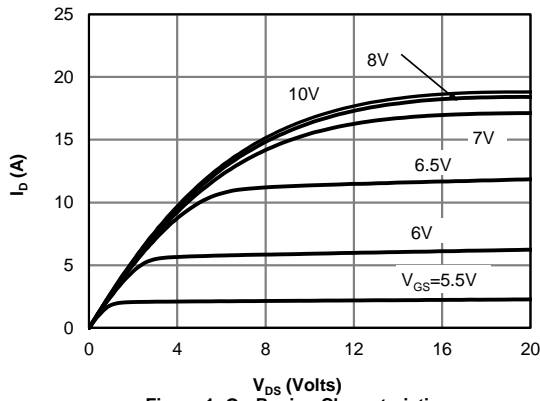
I. C<sub>o(tr)</sub> is a fixed capacitance that gives the same charging time as C<sub>oSS</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>(BR)DSS</sub>.

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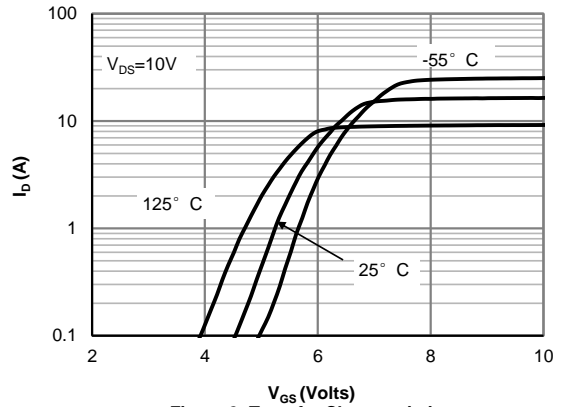
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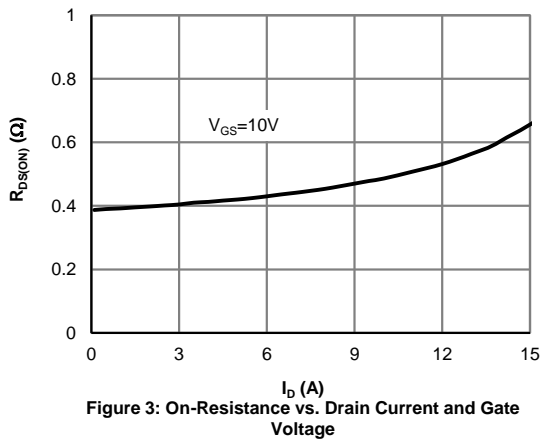
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**



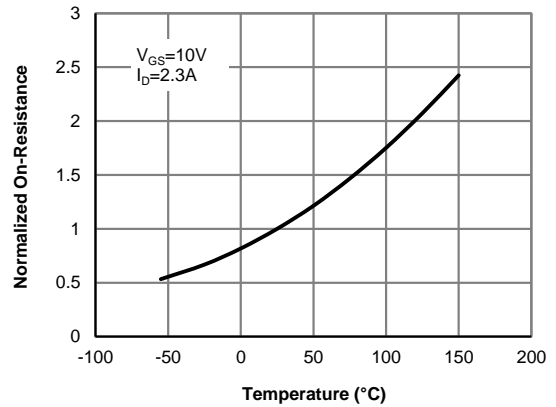
**Figure 1: On-Region Characteristics**



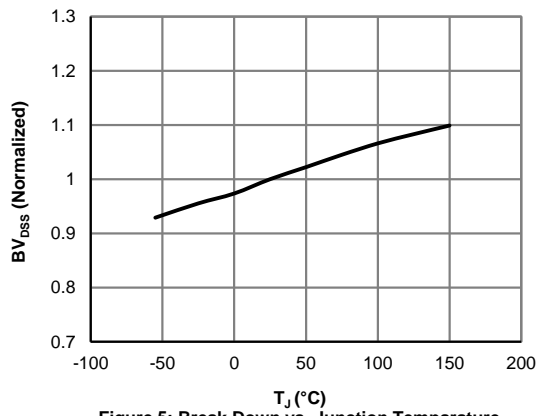
**Figure 2: Transfer Characteristics**



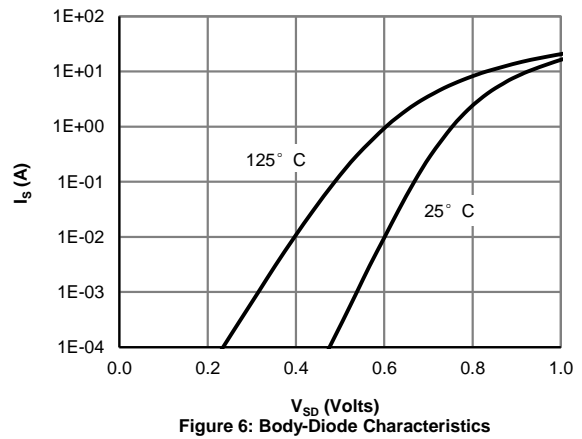
**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**



**Figure 4: On-Resistance vs. Junction Temperature**

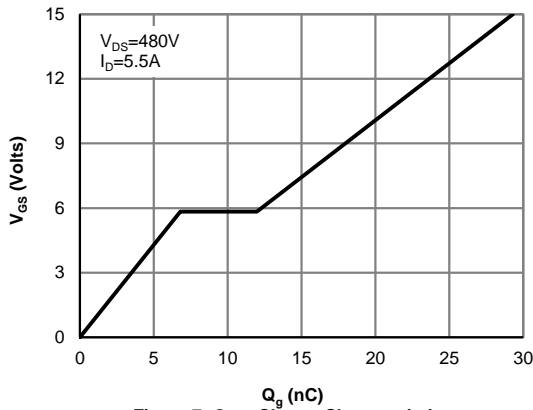


**Figure 5: Break Down vs. Junction Temperature**

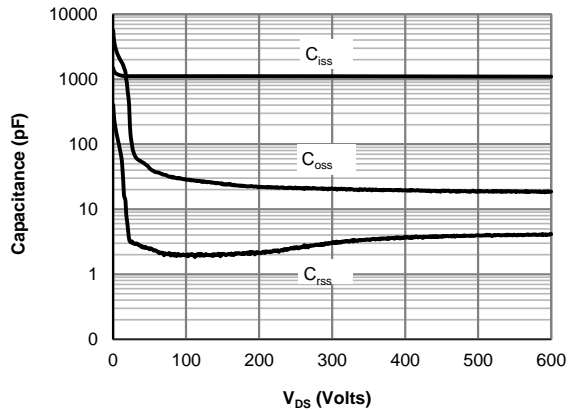


**Figure 6: Body-Diode Characteristics**

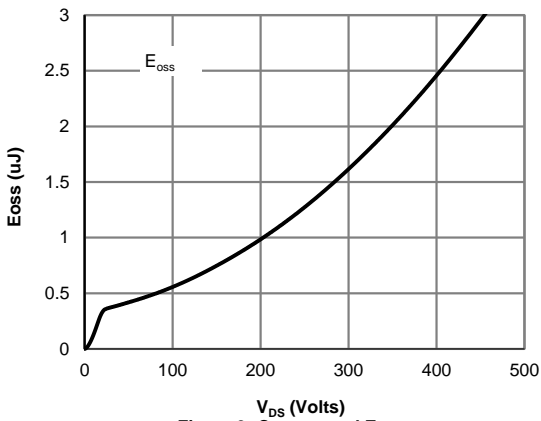
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**



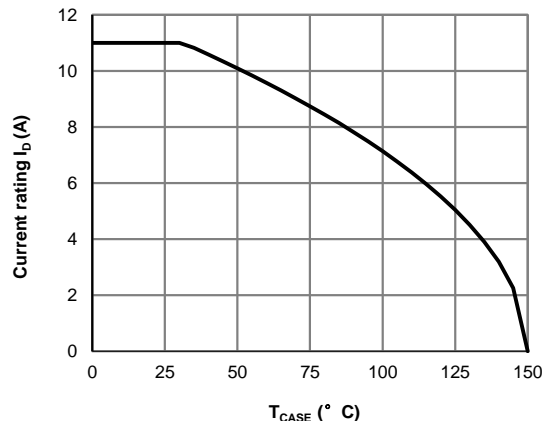
**Figure 7: Gate-Charge Characteristics**



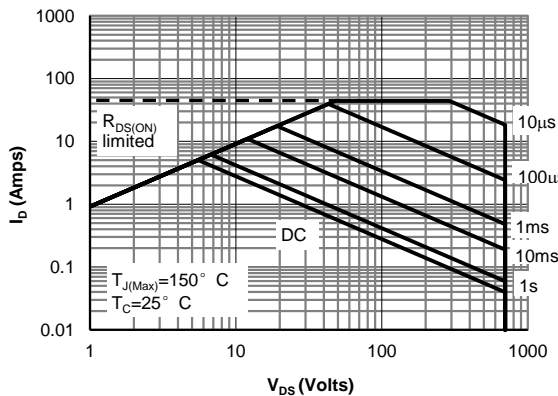
**Figure 8: Capacitance Characteristics**



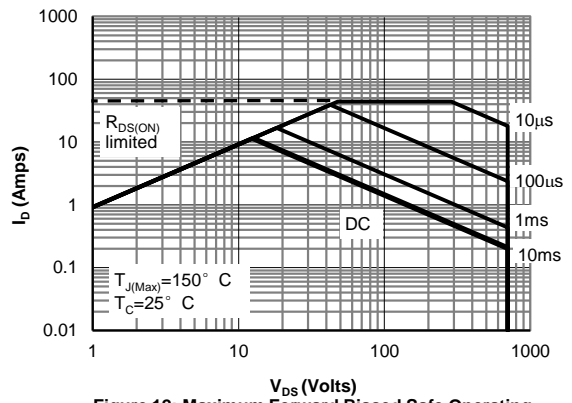
**Figure 9: Coss stored Energy**



**Figure 10: Current De-rating (Note F)**

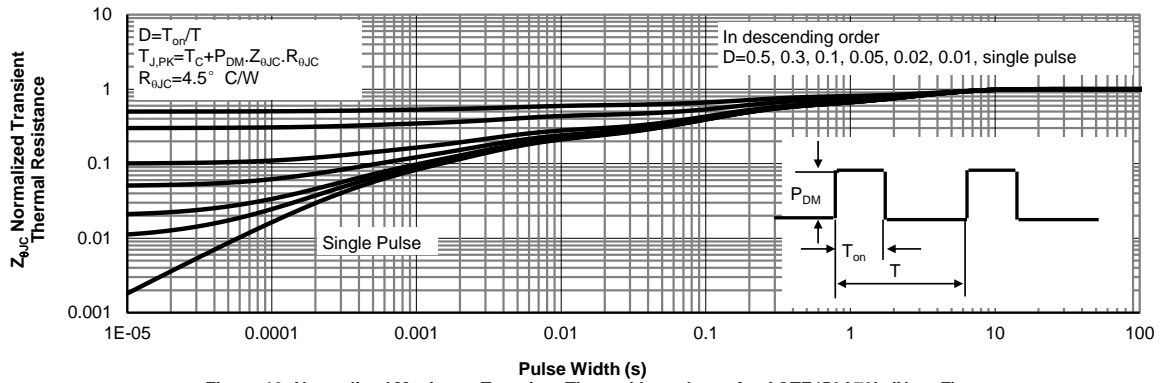


**Figure 11: Maximum Forward Biased Safe Operating Area for AOTF450A70L (Note F)**

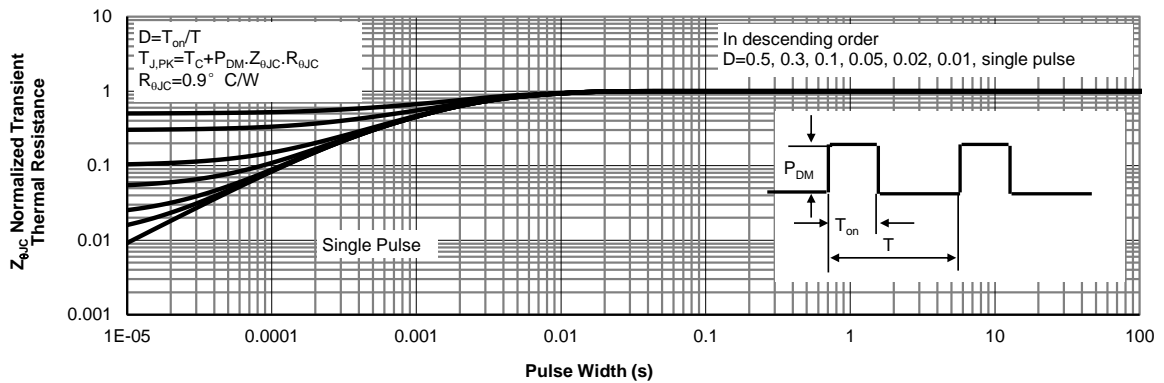


**Figure 12: Maximum Forward Biased Safe Operating Area for AOT(B)450A70L (Note F)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

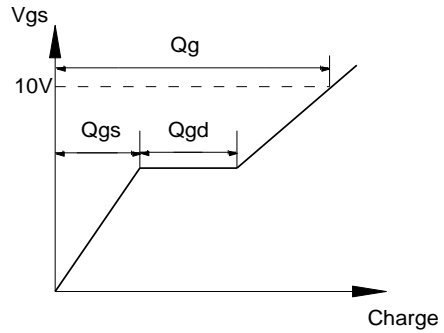
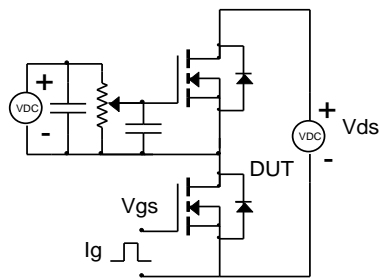


**Figure 13: Normalized Maximum Transient Thermal Impedance for AOTF450A70L (Note F)**

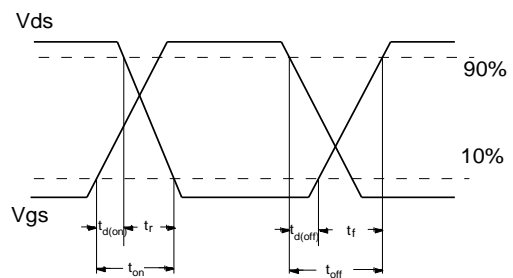
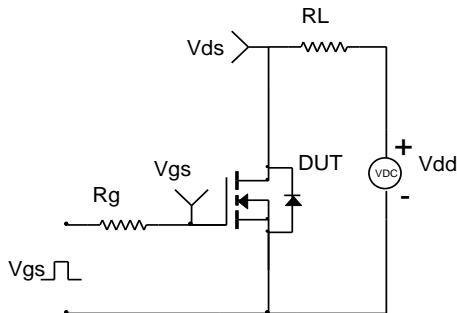


**Figure 14: Normalized Maximum Transient Thermal Impedance for AOT(B)450A70L (Note F)**

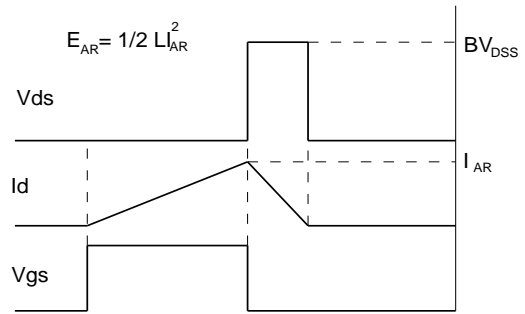
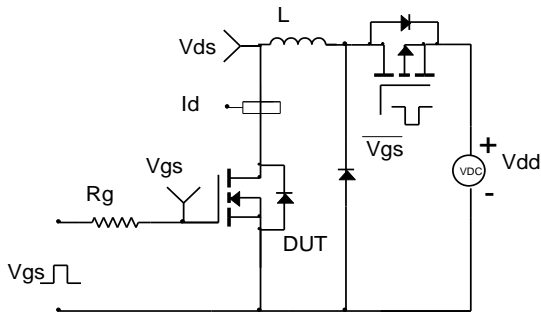
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

